

09/524,625

L Number	Hits	Search Text	DB	Time stamp
1	1032	714/724.ccls.	USPAT	2004/02/24 10:13
2	297	((circuit under test or device under test or unit under test or DUT or UUT or CUT) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)) and (wavform digitizer\$1))) and (((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT))	USPAT; USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:15
3	3637	714/724.ccls. or 714/731.ccls. or 714/726.ccls. or 714/738.ccls. or 714/740.ccls. or 714/744.ccls. or 324/76.11.ccls. or 324/76.12.ccls. or 324/76.77.ccls. or 324/76.82.ccls. or 324/76.83.ccls.	USPAT	2004/02/24 10:17
5	1639321	analog reconstruction filter\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:22
6	404828	extract\$3 and (analog signal\$1 with test signal bit sequence\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:23
7	211083	(analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:24
8	1484854	CUT	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:24
9	50255	((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:24
10	14991	((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:24
11	1244861	arbitrary waveform generator\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:24
12	2782117	clock source	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:25
13	14359	wavform digitizer\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:25

14	734308	(digital signal processor\$1) and (arbitrary waveform generator\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:25
15	4241389	digital signal processor\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:26
16	399465	((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/24 10:27
17	273842	(digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source))	USPAT	2004/02/24 10:28
18	4024	(wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))	USPAT	2004/02/24 10:28
19	4024	((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1)	USPAT	2004/02/24 10:29
20	193	((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1))	USPAT	2004/02/24 10:29
21	193	(((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1)) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)	USPAT	2004/02/24 10:29
22	193	(((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1)) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and ((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))	USPAT	2004/02/24 10:29

23	193	((((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and ((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))	USPAT	2004/02/24 10:30
24	193	((((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and ((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))	USPAT	2004/02/24 10:30
30	1249	714/728.ccls. or 714/39.ccls. or 714/30.ccls. or 714/37.ccls. or 714/799.ccls.	USPAT	2004/02/24 10:35
32	5054	327/? .ccls. or 324/? .ccls. or 714/? .ccls.	USPAT	2004/02/24 10:36
26	193	((((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and ((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and (analog reconstruction filter\$1) and (analog signal\$1 with test signal bit sequence\$1))) and (((circuit under test or device under test or unit under test or DUT or UUT or CUT) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)) and (wavform digitizer\$1))) and (((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test)))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)))	USPAT USPAT	2004/02/24 10:37